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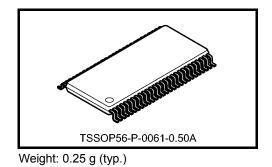
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74VCXH16827FT

Low-Voltage 20-Bit Bus Buffer with Bushold

The TC74VCXH16827FT is a high-performance CMOS 20-bit bus buffer. Designed for use in 1.8-V, 2.5-V or 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

The TC74VCXH16827FT is composed of two 10-bit sections with separate output-enable signals. For either 10-bit buffer section, the two output-enable (1 $\overline{OE1}$ and 1 $\overline{OE2}$ or 2 $\overline{OE1}$ and 2 $\overline{OE2}$) inputs must both be low for the corresponding Y outputs to be active. When the \overline{OE} input is high, the outputs are in a high-impedance state. This device is designed to be used with 3-state memory address drivers, etc.



The A data inputs include active bushold circuitry, eliminating

the need for external pull-up resistors to hold unused or floating data inputs at a valid logic level.

All inputs are equipped with protection circuits against static discharge.

Features

- Low-voltage operation: $V_{CC} = 1.8$ to 3.6 V
- Bushold on data inputs eliminating the need for external pull-up/pull-down resistors
- High-speed operation: $t_{pd} = 2.5 \text{ ns} (max) (V_{CC} = 3.0 \text{ to } 3.6 \text{ V})$
 - : t_{pd} = 3.0 ns (max) (V_{CC} = 2.3 to 2.7 V)
 - : $t_{pd} = 6.0 \text{ ns} (max) (V_{CC} = 1.8 \text{ V})$
- Output current: $I_{OH}/I_{OL} = \pm 24 \text{ mA} (min) (V_{CC} = 3.0 \text{ V})$

:
$$I_{OH}/I_{OL} = \pm 18 \text{ mA} \text{ (min)} (V_{CC} = 2.3 \text{ V})$$

 $: I_{OH}/I_{OL} = \pm 6 \text{ mA} (min) (V_{CC} = 1.8 \text{ V})$

- Latch-up performance: -300 mA
- ESD performance: Machine model $\geq \pm 200$ V

Human body model $\geq \pm 2000 \text{ V}$

- Package: TSSOP
- 3.6-V tolerant function and power-down protection control inputs and outputs

Pin Assignment (top view)

56 10E2 10E1 1 1Y1 2 55 1A1 1Y2 3 54 1A2 GND 4 GND 53 1Y3 5 52 1A3 6 1Y4 51 1A4 7 V_{CC} 50 V_{CC} 1Y5 8 49 1A5 1Y6 9 48 1A6 1Y7 10 47 1A7 GND 11 GND 46 1Y8 12 1A8 45 1Y9 13 1A9 44 1Y10 14 1A10 43 2Y1 15 42 2A1 2Y2 16 2A2 41 2Y3 2A3 17 40 GND 18 GND 39 2Y4 19 2A4 38 2Y5 20 2A5 37 2Y6 21 2A6 36 V_{CC} 22 35 V_{CC} 2Y7 23 34 2A7 2Y8 24 2A8 33 GND 25 GND 32 2Y9 26 31 2A9 2Y10 27 2A10 30 20E1 28 $2\overline{OE2}$ 29

10E1 -	1 _	- &			
10E2 -	56 🗅	_	EN1		
20E1 -	28	- &			
20E2 -	29 🗅	_	EN2		
				0	
1A1 -	55	-	1 1 7	2	· 1Y1
1A2 -	54	-		3	· 1Y2
1A3 -	52	_		5	1Y3
1A4 -	51	_		6	1Y4
1A5 -	49	_		8	· 1Y5
1A6 -	48	_		9	1Y6
1A7 -	47			10	· 1Y7
1A8 -	45			12	· 1Y8
1A9 -	44			13	- 1Y9
1A10 -	43			14	· 1Y10
2A1 -	42	 	1 2 🗸	15	· 2Y1
2A1 - 2A2 -	41		1 2 V	16	211 2Y2
	40			17	
2A3 -	38			19	- 2Y3
2A4 -	37			20	2Y4
2A5 -	36			21	2Y5
2A6 -	34	-		23	2Y6
2A7 -		┨			· 2Y7
2A8 -	33	-		24	2Y8
2A9 -	31	4		26	2Y9
2A10 -	30	-		27	2Y10

IEC Logic Symbol

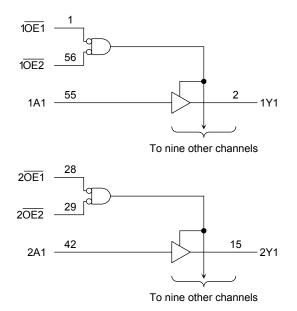
Truth Table (each 10-bit latch)

	Output		
OE1	OE2	А	Y
L	L	L	L
L	L	Н	н
Н	Х	Х	Z
Х	Н	х	Z

X: Don't care

Z: High impedance

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics		Symbol	Rating	Unit
Power supply voltage		V _{CC}	-0.5 to 4.6	V
DC input voltage	(OE)	V	-0.5 to 4.6	V
DC input voltage	(An)	V _{IN}	–0.5 to V _{CC} + 0.5	v
			-0.5 to 4.6 (Note 2)	
DC output voltage		V _{OUT}	–0.5 to V _{CC} + 0.5	V
			(Note 3)	
Input diode current		IIK	-50	mA
Output diode current		I _{OK}	±50 (Note 4)	mA
Output current		IOUT	±50	mA
Power dissipation		PD	400	mW
DC V_{CC}/ground current per supply pin		I _{CC} /I _{GND}	±100	mA
Storage temperature		T _{stg}	–65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 2: OFF state
- Note 3: High or low state. IOUT absolute maximum rating must be observed.
- Note 4: $V_{OUT} < GND, V_{OUT} > V_{CC}$

Operating Ranges (Note 1) (Note 2)

Characteristics		Symbol	Rating	Unit	
Power supply voltage		V _{CC}	1.8 to 3.6	V	
Tower suppry voltage		VCC	1.2 to 3.6 (Note 3)	v	
Input voltage	(OE)	VIN	-0.3 to 3.6	V	
Input voltage	(An)	VIN	0 to V _{CC}	v	
Output voltage	Output upltana		0 to 3.6 (Note 4)	V	
Oulput voltage		Vout	0 to V _{CC} (Note 5)	v	
			±24 (Note 6)		
Output current		I _{OH} /I _{OL}	±18 (Note 7)	mA	
			±6 (Note 8)		
Operating temperature		T _{opr}	-40 to 85	°C	
Input rise and fall time		dt/dv	0 to 10 (Note 9)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

- Note 2: Floating or unused control inputs must be held high or low.
- Note 3: Data retention
- Note 4: OFF state
- Note 5: High or low state
- Note 6: $V_{CC} = 3.0$ to 3.6 V
- Note 7: $V_{CC}=2.3 \mbox{ to } 2.7 \mbox{ V}$
- Note 8: $V_{CC} = 1.8 V$
- Note 9: $V_{IN} = 0.8$ to 2.0 V, $V_{CC} = 3.0$ V

Electrical Characteristics

DC Characteristics (Ta = -40 to 85°C, 2.7 V < V_{CC} \leq 3.6 V)

Characteris	stics	Symbol	Test C	condition	V _{CC} (V)	Min	Max	Unit
	H-level	VIH			2.7 to 3.6	2.0		
Input voltage	L-level	VIH			2.7 to 3.6		0.8	V
		VIL		I _{OH} = -100 μA	2.7 to 3.6	V _{CC} - 0.2		
	H-level	Vон	VIN = VIH or VIL	I _{OH} = -12 mA	2.7	2.2		
		0.11		I _{OH} = -18 mA	3.0	2.4		
Output voltage				I _{OH} = -24 mA	3.0	2.2		V
				I _{OL} = 100 μA	2.7 to 3.6		0.2	
	L-level	vel V_{OL} $V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 12 \text{ mA}$ $I_{OL} = 18 \text{ mA}$		I _{OL} = 12 mA	2.7		0.4	
	L-level		VIN = VIH OL VIL		I _{OL} = 18 mA	3.0		0.4
				I _{OL} = 24 mA	3.0		0.55	
Input leakage	(OE)	lu.	V _{IN} = 0 to 3.6 V	-	2.7 to 3.6		±5.0	
current	(An)	lin	$V_{IN} = V_{CC}$ or GND		2.7 to 3.6	_	±5.0	μA
Bushold input minim	um drive		$V_{IN} = 0.8 V$		3.0	75	_	
hold current		II (HOLD)	V _{IN} = 2.0 V		3.0	-75	_	μA
Bushold input over-	drive current	li van i		(Note 1)	3.6	_	450	
to change state		I _{I (OD)}	OD) (Note 2)		3.6	_	-450	μA
3-state output OFF	state current	I _{OZ}	V _{IN} = V _{IH} or V _{IL} V _{OUT} = 0 to 3.6 V		2.7 to 3.6		±10.0	μΑ
Power-off leakage c	urrent	IOFF	V _{OUT} = 0 to 3.6 V		0	_	10.0	μA
O via sent sent l			V _{IN} = V _{CC} or GND		2.7 to 3.6	_	20.0	
Quiescent supply cu	irrent	ICC			2.7 to 3.6	_	±20.0	μA
Increase in I _{CC} per i	input	∆lcc	$V_{IH} = V_{CC} - 0.6 V$		2.7 to 3.6		750	μA

Note 1: An external driver must source at least the specified current to switch LOW-to-HIGH.

Note 2: An external driver must sink at least the specified current to switch HIGH-to-LOW.

Note 3: Outputs high impedance only.

DC Characteristics (Ta = -40 to 85°C, 2.3 V \leq V_{CC} \leq 2.7 V)

Characteris	etice	Symbol	Test C	Test Condition		Min	Max	Unit
Characteria	51105					IVIIII	IVIAX	Onic
Input voltage	H-level	VIH	-	—	2.3 to 2.7	1.6	_	V
input voltage	L-level	VIL	-		2.3 to 2.7	_	0.7	v
				I _{OH} = -100 μA	2.3 to 2.7	V _{CC} - 0.2		
	H-level	Vон	VIN = VIH or VIL	I _{OH} = -6 mA	2.3	2.0	_	
				I _{OH} = -12 mA	2.3	1.8	_	
Output voltage				I _{OH} = -18 mA	2.3	1.7	_	V
				I _{OL} = 100 μA	2.3 to 2.7	_	0.2	
	L-level	V _{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL} \qquad \begin{array}{c} I_{OL} = 12 \text{ mA} & 2.3 \\ I_{OL} = 18 \text{ mA} & 2.3 \end{array}$	$OL V_{IN} = V_{IH} \text{ or } V_{IL} \qquad I_{OL} = 12 \text{ mA} \qquad 2.3$	2.3	_	0.4	
				I _{OL} = 18 mA		_	0.6	
Input leakage	(OE)	l	V _{IN} = 0 to 3.6 V		2.3 to 2.7	_	±5.0	
current	(An)	lin	$V_{IN} = V_{CC} \text{ or } GND$		2.3 to 2.7	_	±5.0	μA
Bushold input minim	num drive		V _{IN} = 0.7 V		2.3	45	_	^
hold current		II (HOLD)	V _{IN} = 1.6 V		2.3	-45	_	μA
Bushold input over-	drive current			(Note 1)	2.7	_	300	^
to change state		I _{I (OD)}	(Note 2)		2.7	_	-300	μA
			$V_{IN} = V_{IH}$ or V_{IL}		0.040.07		10.0	^
3-state output OFF	state current	I _{OZ}	V _{OUT} = 0 to 3.6 V		2.3 to 2.7	—	±10.0	μA
Power-off leakage of	urrent	I _{OFF}	V _{OUT} = 0 to 3.6 V		0		10.0	μA
	rrant		$V_{IN} = V_{CC}$ or GND	V _{IN} = V _{CC} or GND		_	20.0	
Quiescent supply cu		Icc	$V_{CC} \leq V_{OUT} \leq 3.6 \text{ V}$	(Note 3)	2.3 to 2.7	_	±20.0	μA

Note 1: An external driver must source at least the specified current to switch LOW-to-HIGH.

Note 2: An external driver must sink at least the specified current to switch HIGH-to-LOW.

Note 3: Outputs high impedance only.

DC Characteristics (Ta = -40 to 85°C, 1.8 V \leq V_{CC} < 2.3 V)

Characteris	stics	Symbol	Test C	ondition	V _{CC} (V)	Min	Max	Unit		
Input voltage	H-level	VIH	-	_	1.8 to 2.3	$0.7 \times V_{CC}$	_	V		
input voltage	L-level	V _{IL}	-	_	1.8 to 2.3	_	$0.2 \times V_{CC}$	v		
	H-level	Vон	VIN = VIH or VIL	I _{OH} = -100 μA	1.8	V _{CC} - 0.2	_			
Output voltage				I _{OH} = -6 mA	1.8	1.4	_	V		
	L-level	Voi	Very Very or Ver	I _{OL} = 100 μA	1.8	_	0.2			
	L-level	VOL	$I_{OL} = 6 \text{ mA} $ 1.8	$I_{OL} = 6 \text{ mA} $ 1.8	$I_{OL} = 6 \text{ mA}$ 1.8	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 6 \text{ mA}$		_	0.3	
Input leakage	(OE)	I _{IN}	$V_{IN} = 0$ to 3.6 V		1.8	_	±5.0	μA		
current	(An)	NI	$V_{IN} = V_{CC}$ or GND	$V_{IN} = V_{CC}$ or GND		_	±5.0	μA		
Bushold input minim	um drive		V _{IN} = 0.36 V		1.8	25	_	μA		
hold current		II (HOLD)	V _{IN} = 1.26 V		1.8	-25	_	μA		
Bushold input over-	drive current	lu (op)		(Note 1)	1.8		200	μA		
to change state	nge state			(Note 2)	1.8		-200	μA		
3 state output OEE	stato curront	107	$V_{IN} = V_{IH} \text{ or } V_{IL}$		1.8		±10.0			
3-state output OFF state current I _{OZ}		102	V _{OUT} = 0 to 3.6 V		1.0		±10.0	μA		
Power-off leakage c	urrent	IOFF	V _{OUT} = 0 to 3.6 V		0		10.0	μA		
Quiescent supply cu	irront		$V_{IN} = V_{CC} \text{ or } GND$		1.8	_	20.0			
Quiescent supply cu		Icc	$V_{CC} \leq V_{OUT} \leq 3.6 \text{ V}$	(Note 3)	1.8		±20.0	μA		

Note 1: An external driver must source at least the specified current to switch LOW-to-HIGH.

Note 2: An external driver must sink at least the specified current to switch HIGH-to-LOW.

Note 3: Outputs high impedance only.

AC Characteristics (Ta = -40 to 85°C, input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500 \Omega$) (Note 1)

Characteristics	Symbol	Test Condition		Min	Max	Unit
			$V_{CC}(V)$			
	+		1.8	1.5	6.0	
Propagation delay time	t _{pLH} t _{pHL}	Figure 1, Figure 2	2.5 ± 0.2	1.0	3.0	ns
	γn∟		$\textbf{3.3}\pm\textbf{0.3}$	0.8	2.5	
	t		1.8	1.5	9.8	
3-state output enable time	t _{pZL} t _{pZH}	Figure 1, Figure 3	2.5 ± 0.2	1.0	4.9	ns
			$\textbf{3.3}\pm\textbf{0.3}$	0.8	3.8	
	t . –		1.8	1.5	7.6	
3-state output disable time	t _{pLZ}	Figure 1, Figure 3	2.5 ± 0.2	1.0	4.2	ns
	t _{pHZ}		$\textbf{3.3}\pm\textbf{0.3}$	0.8	3.7	
	•		1.8	_	0.5	
Output to output skew	t _{osLH}	(Note 2)	2.5 ± 0.2		0.5	ns
	t _{osHL}		3.3 ± 0.3	_	0.5	

Note 1: For $C_L = 50 \text{ pF}$, add approximately 300 ps to the AC maximum specification.

Note 2: Parameter guaranteed by design.

Dynamic Switching Characteristics

(Ta = 25°C, input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500 \Omega$)

Characteristics	Symbol	Test Condition			Тур.	Unit
	Cymbol			$V_{CC}\left(V\right)$.)p.	onit
		$V_{IH} = 1.8 V, V_{IL} = 0 V$ (N	ote)	1.8	0.25	
Quiet output maximum dynamic V _{OI}	V _{OLP}	$V_{IH} = 2.5 V, V_{IL} = 0 V$ (N	ote)	2.5	0.6	V
,		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (N	ote)	3.3	0.8	
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (N	ote)	1.8	-0.25	
Quiet output minimum dynamic V _{OI}	V _{OLV}	$V_{IH} = 2.5 V, V_{IL} = 0 V$ (N	ote)	2.5	-0.6	V
, 02		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (N	ote)	3.3	-0.8	
		$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (N	ote)	1.8	1.5	
Quiet output minimum dynamic V _{OH}	V _{OHV}	$V_{IH} = 2.5 V, V_{IL} = 0 V$ (N	ote)	2.5	1.9	V
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (N	ote)	3.3	2.2	

Note: Parameter guaranteed by design.

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition			Тур.	Unit
Characteristics	Symbol			V _{CC} (V)	тур.	Offic
Input capacitance	C _{IN}			1.8, 2.5, 3.3	6	pF
Output capacitance	C _{OUT}			1.8, 2.5, 3.3	7	pF
Power dissipation capacitance	C _{PD}	$f_{IN} = 10 \text{ MHz}$ (Note)	1.8, 2.5, 3.3	20	pF

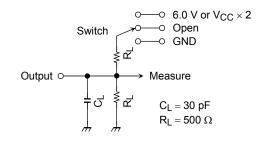
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/20$ (per bit)

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AC Test Circuit



Parameter	Switch		
t _{pLH} , t _{pHL}	Open		
t _{pLZ} , t _{pZL}			
t _{pHZ} , t _{pZH}	GND		

Figure 1

AC Waveform

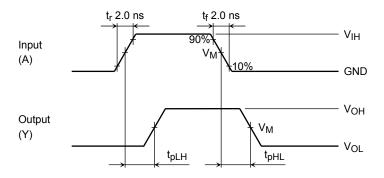
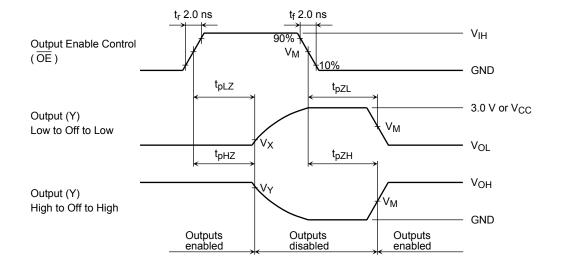


Figure 2 t_{pLH}, t_{pHL}

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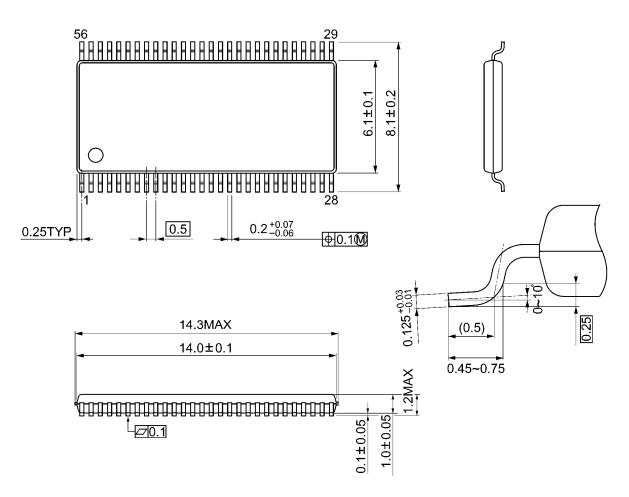
Symbol	V _{CC}							
Symbol	$3.3\pm0.3~V$	$2.5\pm0.2~\text{V}$	1.8 V					
VIH	2.7 V	V _{CC}	V _{CC}					
VM	1.5 V	V _{CC} /2	V _{CC} /2					
VX	V _{OL} + 0.3 V	V _{OL} + 0.15 V	V _{OL} + 0.15 V					
VY	V _{OH} – 0.3 V	V _{OH} – 0.15 V	V _{OH} – 0.15 V					

Figure 3 t _{pLZ} , t _{pHZ} , t _{pZL} , t _p	ZH
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Package Dimensions

TSSOP56-P-0061-0.50A

Unit: mm



Weight: 0.25 g (typ.)

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20070701-EN GENERAL

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